

Description

The AP5N20D-H is silicon N-channel Enhanced

VDMOSFETs, is obtained by the self-aligned planar Technology

which reduce the conduction loss, improve switching

performance and enhance the avalanche energy. The transistor

can be used in various power switching circuit for system

miniaturization and higher efficiency.

General Features

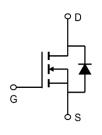
VDS =200V,ID =5A

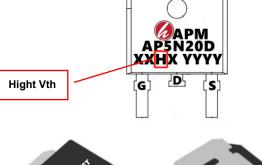
RDS(ON) <600m Ω @ VGS=10V (Type: 530m Ω)

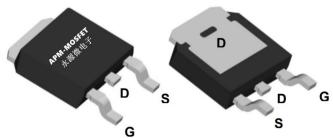
Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)







Package Marking and Ordering Information

	Qty(PCS)
AP5N20D-H TO-252-3L AP5N20D-H XXX YYYY	2500

Absolute Maximum Ratings T_C = 25°C, unless otherwise noted **Symbol Parameter** Value Unit **VDSS** Drain-Source Voltage (V_{GS} = 0V) 200 I_D **Continuous Drain Current** 5 Α 20 IDM **Pulsed Drain Current** Α **VGSS** Gate-Source Voltage V ±20 45 Eas Single Pulse Avalanche Energy mJ IAR **Avalanche Current** 3 Α E_{AR} Repetitive Avalanche Energy 3.2 mJ P_D Power Dissipation (T_C = 25°C) 46 W RthJC °C/W Thermal Resistance, Junction-to-Case 2.7 °C/W RthJA Thermal Resistance, Junction-to-Ambient 60 -55~+150 Operating Junction and Storage Temperature Range ٥С TJ, Tstg





Electrical Characteristics (TJ=25℃, unless otherwise noted)

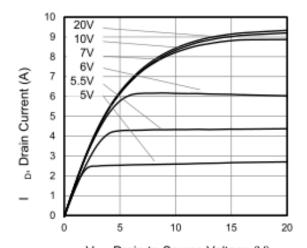
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	rage $V_{GS} = 0V$, $I_D = 250\mu A$		221	-	٧
IDSS	Zava Cata Valta na Dunin Cumunt	V _{DS} = 200V, V _{GS} = 0V, T _J = 25°C	-		5	
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 160V, V _{GS} = 0V, T _J = 125°C	-		100	μA
IGSS	Gate-Source Leakage	V _{GS} = ±20V			±100	nΑ
VGS(th)	Gate-Source Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	2.5	3.1	4.0	٧
RDS(on)	Drain-Source On-Resistance (Note3)	V _{GS} = 10V, I _D = 2.5A		530	600	mΩ
C _{iss}	Input Capacitance			228		
Coss	Output Capacitance	$V_{GS} = 0V,$ $V_{DS} = 25V, f = 1.0MHz$		48		pF
Crss	Reverse Transfer Capacitance	VDS = 20 V, 1 = 1.0WH12		17		
Qg	Total Gate Charge			18		nC
Q _{gs}	Gate-Source Charge	V_{DD} = 160V, I_{D} = 5.0A, V_{GS} = 10V		1.5		
Q _{gd}	Gate-Drain Charge	100		9.5		
td(on)	Turn-on Delay Time			10		
t _r	Turn-on Rise Time	$V_{DD} = 100V, I_D = 5.0A, R_G = 25$	-	19	-	ns
td(off)	Turn-off Delay Time	Ω	-	43		
t _f	Turn-off Fall Time		-	32		
ls	Continuous Body Diode Current	T - 25.00			5	^
ISM	Pulsed Diode Forward Current	T _C = 25 ℃			20	Α
V _{SD}	Body Diode Voltage	T _J = 25°C, I _{SD} = 5A, V _{GS} = 0V			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V,I _S = 5A, di _F /dt =100A		160		ns
Qrr	Reverse Recovery Charge	/µs		1.5		μC

Note:

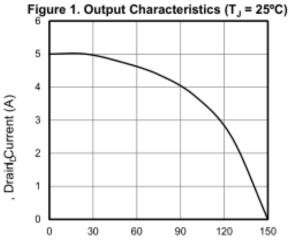
- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The EAS data shows Max. rating . IAS = 3A, VDD = 50V, RG = 25 Ω , Starting TJ = 25 $^{\circ}$ C
- 3、The test condition is Pulse Test: Pulse width ≤ $300\mu s$, Duty Cycle ≤ 1%
- 4、The power dissipation is limited by 150 $^{\circ}\mathrm{C}$ junction temperature
- 5、The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics



V_{DS}, Drain-to-Source Voltage (V)



T_C, Case Temperature (A)

Figure 3. Drain Current vs. Temperature

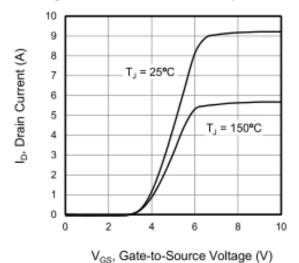


Figure 5. Transfer Characteristics

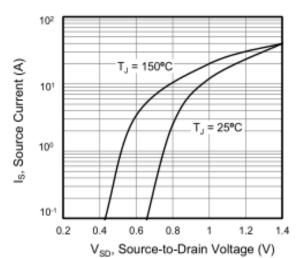
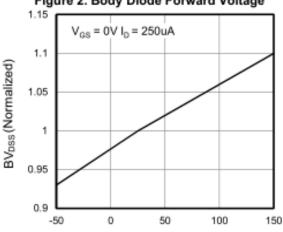
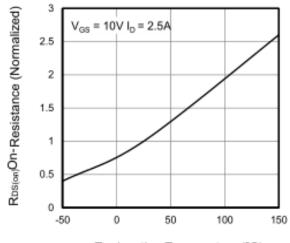


Figure 2. Body Diode Forward Voltage



T_J, Junction Temperature (°C)

Figure 4. BV_{DSS} Variation vs. Temperature



T_J, Junction Temperature (°C)

Figure 6. On-Resistance vs. Temperature





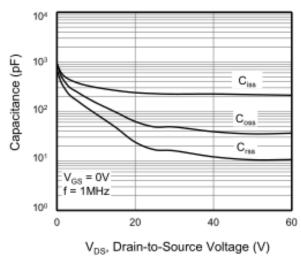


Figure 7. Capacitance

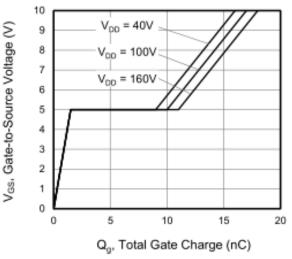


Figure 8. Gate Charge

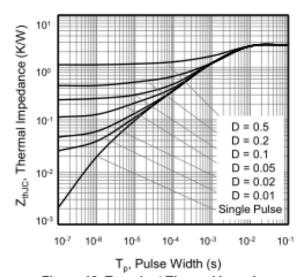


Figure 10. Transient Thermal Impedance

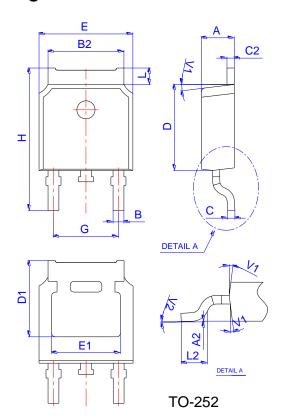






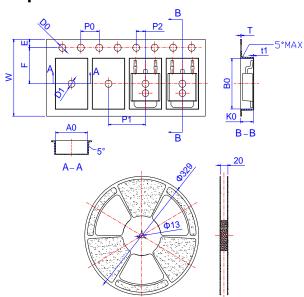


Package Mechanical Data:TO-252-3L



	Dimensions						
Ref.		Millimeter	rs	Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			0.209REF			
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO-252



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
W	15.90	16.00	16.10	0.626	0.630	0.634	
Е	1.65	1.75	1.85	0.065	0.069	0.073	
F	7.40	7.50	7.60	0.291	0.295	0.299	
D0	1.40	1.50	1.60	0.055	0.059	0.063	
D1	1.40	1.50	1.60	0.055	0.059	0.063	
P0	3.90	4.00	4.10	0.154	0.157	0.161	
P1	7.90	8.00	8.10	0.311	0.315	0.319	
P2	1.90	2.00	2.10	0.075	0.079	0.083	
A0	6.85	6.90	7.00	0.270	0.271	0.276	
В0	10.45	10.50	10.60	0.411	0.413	0.417	
K0	2.68	2.78	2.88	0.105	0.109	0.113	
Т	0.24		0.27	0.009		0.011	
t1	0.10			0.004			
10P0	39.80	40.00	40.20	1.567	1.575	1.583	







200V N-Channel Enhancement Mode MOSFET Attention

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AP5N20D-H

200V N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2020/5/31	Initial release
Rve1.1	2020/3/15	Change layout format

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